

FCC ID: 2APDQMPBT-H01

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW})/(\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHZ})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHZ})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

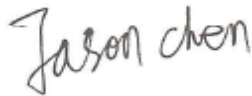
When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	6.96	4.97	7.61±1	8.61	7.26	<5	2.25069	3.00	YES
	2.441	8.61	7.26	7.61±1	8.61	7.26	<5	2.26889	3.00	YES
	2.480	7.33	5.41	7.61±1	8.61	7.26	<5	2.28695	3.00	YES
π/4-DQPSK	2.402	4.61	2.89	4.8±1	5.8	3.80	<5	1.17846	3.00	YES
	2.441	5.77	3.78	4.8±1	5.8	3.80	<5	1.18799	3.00	YES
	2.480	5.33	3.41	4.8±1	5.8	3.80	<5	1.19745	3.00	YES
8DPSK	2.402	5.18	3.30	5.9±1	6.9	4.90	<5	1.51816	3.00	YES
	2.441	6.90	4.90	5.9±1	6.9	4.90	<5	1.53043	3.00	YES
	2.480	5.72	3.73	5.9±1	6.9	4.90	<5	1.54261	3.00	YES
BLE	2.402	7.36	5.45	8±1	9	7.94	<5	2.46216	3.00	YES
	2.44	8.91	7.78	8±1	9	7.94	<5	2.48156	3.00	YES
	2.48	8.64	7.31	8±1	9	7.94	<5	2.50182	3.00	YES

Conclusion:

For the max result : 2.50182W/Kg ≤ 3.0 for 1g SAR, No SAR is required.



Signature:

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